Sea	earch Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/812,355	YUE, HONGYU
Examiner	Art Unit
Kin-Chan Chen	1765

SEARCHED					
Class	Subclass	Date	Examiner		
438 i	706	1/3/2006	ксс		
	714				
J	715				
438	723				
216	63				
216	74	Y3/06	Kcc		

INT	INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Keywords scarch USPAT, USPG-Pub. Epo, TPO, Derwent VBM-TDB, inventorscarch	1/3/2006	ксс		
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